Crack propagation in heterogeneous materials with several defects

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Italian/British Workshop on Fluid & Solids Interaction and Fracture & Failure of Solids and Structures 16 August 2011



This research has been supported by the European Union under a Marie Curie Intra-European Fellowship for Career Development FP7-PEOPLE-2009-IEF-252857 "INTERCRACKS"



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The problem and motivation



Crack advancing in a bimaterial plane with finite array of defects

- What is the effect of the defects on the propagation of the crack? Amplification/shielding effects?
- Can we arrange the defects in such a way to stop the propagation of the crack?
- Vice versa, can we arrange the defects in such a way to make the crack propagate up to the end of the array?

New challenges:

- Interfacial crack
- Weight function for an interfacial crack
- Singular perturbation procedure related to small defects
- Singular perturbation procedure related to small advance of the crack

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Type of defects

- Small elastic inclusions
- Small voids
- Small rigid inclusions
- Microcracks
- Rigid line inclusions

Line defect with imperfect bonding:

• Line defect with soft bonding (stiffness κ): $[\![\sigma]\!](s) = 0$, $\sigma(s) = \kappa[\![u]\!](s)$

 $\left\{ \begin{array}{ll} \kappa = 0 & \Rightarrow & \sigma(s) = 0 & \text{microcrack} \\ \kappa = \infty & \Rightarrow & \llbracket u \rrbracket(s) = 0 & \text{perfect bonding (no defect)} \end{array} \right.$

• Stiff line defect (stiffness κ): $\llbracket u \rrbracket(s) = 0$, $\llbracket \sigma \rrbracket(s) + \kappa \left. \frac{\partial^2 u}{\partial s^2} \right|_{\gamma^{\epsilon}} = 0$

$$\begin{cases} \kappa = 0 \quad \Rightarrow \quad [\![\sigma]\!](s) = 0 \quad \text{no defect} \\ \kappa = \infty \quad \Rightarrow \quad \frac{\partial^2 u}{\partial s^2} \Big|_{\gamma^{\epsilon}} = 0 \quad \text{rigid line inclusion} \end{cases}$$



Problem formulation

Bimaterial plane with a dominant crack along the interface and small defects:



Singular perturbations:

- Elastic inclusion
- 2 Microcrack
- Rigid line inclusion

Singular perturbation:

Crack advance

Small parameter ε : diameter of defect $2\varepsilon l, \varepsilon \ll 1$

Assumptions:

- Mode III deformation
- 2 Loading on the crack surfaces
- Perfect interfaces (continuity of displacements and tractions)
- The composite is dilute (neglect interactions between small defects)
- Stable quasi-static propagation (neglect inertia terms)



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$$u(\boldsymbol{x},\varepsilon) = u^{(0)}(\boldsymbol{x}) + \left[\varepsilon \sum_{j=1}^{3} W_j(\boldsymbol{\xi}_j)\right] + \varepsilon^2 \sum_{j=1}^{3} u^{(j)}(\boldsymbol{x}) + \varepsilon^2 v(\boldsymbol{x},\phi) + o(\varepsilon^2), \quad \varepsilon \to 0$$



Solution of the unperturbed problem (ε = 0)
 Boundary layers concentrated near the defects

$$u(\boldsymbol{x},\varepsilon) = u^{(0)}(\boldsymbol{x}) + \varepsilon \sum_{j=1}^{3} W_j(\boldsymbol{\xi}_j) + \varepsilon^2 \sum_{j=1}^{3} u^{(j)}(\boldsymbol{x}) + \varepsilon^2 v(\boldsymbol{x},\phi) + o(\varepsilon^2), \quad \varepsilon \to 0$$



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- Boundary layers concentrated near the defects
- Additional terms to adjust the BC and IC disturbed by the boundary layers

$$u(\mathbf{x},\varepsilon) = u^{(0)}(\mathbf{x}) + \varepsilon \sum_{j=1}^{3} W_j(\boldsymbol{\xi}_j) + \varepsilon^2 \sum_{j=1}^{3} u^{(j)}(\mathbf{x}) + \varepsilon^2 v(\mathbf{x},\phi) + o(\varepsilon^2), \quad \varepsilon \to 0$$



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- Boundary layers concentrated near the defects
- Additional terms to adjust the BC and IC disturbed by the boundary layers
- Perturbation associated with the crack advance $\varepsilon^2 \phi$

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Solution of the unperturbed problem ($\varepsilon = 0$)

Boundary layers concentrated near the defects

Additional terms to adjust the BC and IC disturbed by the boundary layers

Perturbation associated with the crack advance $\varepsilon^2 \phi$

- Using the linearity of the problem, we analyse the perturbation of each defect separately (superposition principle).
- The method can be extended to a finite number of defects, provided that the distance between defects remains finite (composite is dilute).

The first challenge: Weight functions for an interfacial crack

"Weight functions are fundamental solutions for the problem of a cracked body"

Linear elasticity:

Linear fracture mechanics:

Interfacial crack:



Green's function for elastic body



Point forces

Weight functions for cracked homogeneous body

Weight functions for interfacial crack

?

$$u_i(\boldsymbol{x}, \boldsymbol{y}) = G_{ij}(\boldsymbol{x}, \boldsymbol{y})e_j$$

$$K = \sqrt{\frac{2}{\pi}} (1+i)a^{-1/2}$$

The weight functions for an interfacial crack

Mode III symmetric and skew-symmetric weight functions:

$$\llbracket U_3 \rrbracket(x_1) = \begin{cases} \frac{1-i}{\sqrt{2\pi}} x_1^{-1/2}, & \text{for } x_1 > 0, \\ 0, & \text{for } x_1 < 0, \end{cases} \quad \langle U_3 \rangle = \frac{\eta}{2} \llbracket U_3 \rrbracket;$$

Integral formula for the computation of the Mode III SIF:

$$\begin{split} K_{\text{III}} &= -(1+i) \lim_{x_1' \to 0^+} \int_{-\infty}^0 \{ \underbrace{\llbracket U_3 \rrbracket (x_1' - x_1) \langle p_3 \rangle (x_1)}_{\text{symmetric part}} + \underbrace{\langle U_3 \rangle (x_1' - x_1) \llbracket p_3 \rrbracket (x_1)}_{\text{skew-symmetric part}} \} dx_1 \\ \eta &= \frac{\mu_- - \mu_+}{\mu_- + \mu_+} \quad \text{bimaterial parameter} \end{split}$$

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The second challenge: singular perturbation for a small defect



The defect is replaced by "effective" tractions

Dipole field:

$$\varepsilon^2 w(\mathbf{x}) = -\frac{\varepsilon^2}{2\pi} \left[\nabla u^{(0)} \Big|_{\mathbf{Y}} \right] \cdot \left[\mathbf{\mathcal{M}} \frac{\mathbf{x} - \mathbf{Y}}{|\mathbf{x} - \mathbf{Y}|^2} \right] + o(\varepsilon^2), \quad \varepsilon \to 0$$

M is the dipole matrix

Perturbation of the SIF:

$$\Delta K_{\rm III} = -\sqrt{\frac{2}{\pi}} \frac{\mu_+\mu_-}{\mu_++\mu_-} \nabla u^{(0)} \Big|_{\mathbf{Y}} \cdot \mathcal{M}c$$

$$c = \frac{1}{2d^{3/2}} \left[-\sin \frac{3\varphi}{2}, \cos \frac{3\varphi}{2} \right]$$

Example: Elliptic elastic inclusion



Dipole field:

$$\varepsilon^2 w(\mathbf{x}) = -\frac{\varepsilon^2}{2\pi} \left[\left. \nabla u^{(0)} \right|_{\mathbf{Y}} \right] \cdot \left[\mathbf{\mathcal{M}} \frac{\mathbf{x} - \mathbf{Y}}{|\mathbf{x} - \mathbf{Y}|^2} \right] + o(\varepsilon^2), \quad \varepsilon \to 0$$

Dipole matrix

$$\mathcal{M} = -\frac{\pi}{2}ab(1+e)(\mu_{\star}-1) \begin{bmatrix} \frac{1+\cos 2\alpha}{e+\mu_{\star}} + \frac{1-\cos 2\alpha}{1+e\mu_{\star}} & -\frac{(1-e)(\mu_{\star}-1)\sin 2\alpha}{(e+\mu_{\star})(1+e\mu_{\star})} \\ -\frac{(1-e)(\mu_{\star}-1)\sin 2\alpha}{(e+\mu_{\star})(1+e\mu_{\star})} & \frac{1-\cos 2\alpha_{1}}{e+\mu_{\star}} + \frac{1+\cos 2\alpha}{1+e\mu_{\star}} \end{bmatrix}$$

$$\mu_{\star} = \mu/\mu_i \qquad e = b/a$$

Dipole matrix for different types of defects

microcrack	$\mathcal{M} = -\pi l^2 \begin{bmatrix} \sin^2 \alpha & -\sin \alpha \cos \alpha \\ -\sin \alpha \cos \alpha & \cos^2 \alpha \end{bmatrix}$
rigid line inclusion	$\mathcal{M} = \pi l^2 \begin{bmatrix} \cos^2 \alpha & \sin \alpha \cos \alpha \\ \sin \alpha \cos \alpha & \sin^2 \alpha \end{bmatrix}$
elliptic void	$\mathcal{M} = -\frac{\pi}{2}ab(1/e+1) \begin{bmatrix} 1 - \cos 2\alpha + e(1 + \cos 2\alpha) & -(1-e)\sin 2\alpha \\ -(1-e)\sin 2\alpha & 1 + \cos 2\alpha + e(1 - \cos 2\alpha) \end{bmatrix}$
elliptic rigid inclusion	$\mathcal{M} = \frac{\pi}{2}ab(1/e+1) \begin{bmatrix} 1+\cos 2\alpha + e(1-\cos 2\alpha) & (1-e)\sin 2\alpha \\ (1-e)\sin 2\alpha & 1-\cos 2\alpha + e(1+\cos 2\alpha) \end{bmatrix}$
line defect (soft)	$\mathcal{M} = -\frac{\pi}{2} \frac{l^2}{\kappa l + 1} \begin{bmatrix} 1 - \cos 2\alpha & -\sin 2\alpha \\ -\sin 2\alpha & 1 + \cos 2\alpha \end{bmatrix}$
line defect (stiff)	$\mathcal{M} = \frac{\pi}{2} \frac{\kappa l^2}{\kappa + l} \begin{bmatrix} 1 + \cos 2\alpha & \sin 2\alpha \\ \sin 2\alpha & 1 - \cos 2\alpha \end{bmatrix}$

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Application: Shielding and amplification effects

$$\Delta K_{\text{III}} = -\sqrt{\frac{2}{\pi}} \frac{\mu_{+}\mu_{-}}{\mu_{+} + \mu_{-}} \nabla u^{(0)} \Big|_{\boldsymbol{Y}} \cdot \boldsymbol{\mathcal{M}}\boldsymbol{c}$$

Definition:

 $\Delta K_{\rm III} < 0$: shielding effect $\Delta K_{\rm III} > 0$: amplification effect $\Delta K_{\rm III} = 0$: neutral "the defect is *preventing* the propagation" "the defect is *promoting* the propagation" "the defect has no effect"

Example: shielding/amplification diagrams for macro-microcrack interaction



The third challenge: Singular perturbation for crack advance



The Betti identity:

$$\int_{-\infty}^{\infty} \left\{ \llbracket U \rrbracket (x_1' - x_1) \langle \sigma \rangle (x_1) + \langle U \rangle (x_1' - x_1) \llbracket \sigma \rrbracket (x_1) - \langle \Sigma \rangle (x_1' - x_1) \llbracket u \rrbracket (x_1) \right\} dx_1 = 0$$

 u, σ physical solution

 U, Σ weight functions

Perturbation of the SIF:

$$\varepsilon^2 \Delta K^{\phi}_{\rm III} = \frac{\varepsilon^2 \phi}{2} A^{(0)}_{\rm III}$$

$$A_{\rm III}^{(0)} = \sqrt{\frac{2}{\pi}} \int_{-\infty}^{0} \left(\langle p \rangle(x_1) + \frac{\eta}{2} [\![p]\!](x_1) \right) (-x_1)^{-3/2} dx_1$$

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Analysis of a stable quasi-static propagation

The stress intensity factor is expanded as follows:

$$K_{\rm III} = K_{\rm III}^{(0)} + \varepsilon^2 \left(\Delta K_{\rm III}^{\phi} + \sum_{j=1}^3 \Delta K_{\rm III}^{(j)} \right) + o(\varepsilon^2), \quad \varepsilon \to 0$$

 $\Delta K^{\phi}_{\rm III} = \frac{\varepsilon^2 \phi}{2} A^{(0)}_{\rm III} : \text{perturbation produced by the}_{\substack{\text{elongation of the crack along the}\\interface}} \sum_{i=1}^{N} \frac{1}{2} \sum_{i=1}^{N}$

$$\sum_{j=1}^{3} \Delta K_{\mathrm{III}}^{(j)}$$
 : perturbation produced by the defects

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We assume that the crack propagation is stable and quasi-static: $G = G_c$

$$G = \frac{1}{4} \left(\frac{1}{\mu_+} + \frac{1}{\mu_-} \right) K_{\mathrm{III}}^2 \quad \Rightarrow \quad \Delta K_{\mathrm{III}}^{\phi} + \sum_{j=1}^3 \Delta K_{\mathrm{III}}^{(j)} = 0 \quad \Rightarrow \quad \left(\phi = \frac{2}{A_{\mathrm{III}}^{(0)}} \sum_{j=1}^3 \Delta K_{\mathrm{III}}^{(j)} \right)$$

$$\Delta K_{\rm III}^{(j)} = -\sqrt{\frac{2}{\pi}} \frac{\mu_{+} \mu_{-}}{\mu_{+} + \mu_{-}} \nabla u^{(0)} \Big|_{\boldsymbol{Y}_{j}} \cdot \boldsymbol{\mathcal{M}}_{j} \boldsymbol{c}_{j}, \qquad \boldsymbol{c}_{j} = \frac{1}{2d_{j}^{3/2}} \left[-\sin\frac{3\varphi_{j}}{2}, \cos\frac{3\varphi_{j}}{2} \right]$$

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Application: Crack propagation and arrest



 $\sum_{i=1}^{2^{\varepsilon l_i}}$ Given a configuration of defects and position of the crack tip, the incremental crack advance ϕ is given by:

$$\phi = \frac{2}{A_{\mathrm{III}}^{(0)}} \sum_{j=1}^{3} \Delta K_{\mathrm{III}}^{(j)}$$

It is possible to update the configuration with the new position of the crack tip and recompute the incremental crack advance in the new configuration, following an iterative procedure:

- the crack "accelerates" when the increment ϕ is increasing
- the crack "decelerates" when the increment ϕ is decreasing
- the crack "arrests" when a neutral configuration is reached ($\phi = 0$)

The total crack elongation is computed as:

$$x(N) = \sum_{i=0}^{N} \varepsilon^2 \phi_i$$

where N is the number of iterations.

Crack propagation in a finite array of defects



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Conclusions and possible extensions

This asymptotic method can be extended to the case of an infinite array of defects

$$2h$$

$$j = -3 -2 -1 0 1 2w 3 4 5$$

$$h$$

$$j = -N^{-}, ..., -1$$

$$j = 1, ..., N^{+}$$

$$-4w -2w 0 2w 4w$$

$$\phi = \frac{al^2 \cos 2\alpha}{2h^2} \left\{ -1 + \sum_{j=1}^{N^+} \frac{\left(1 - \frac{h^2}{j^2 w^2}\right) \frac{h^2}{j^2 w^2}}{\left(1 + \frac{h^2}{j^2 w^2}\right)^2} + \sum_{j=1}^{N^-} \frac{\left(1 - \frac{h^2}{j^2 w^2}\right) \frac{h^2}{j^2 w^2}}{\left(1 + \frac{h^2}{j^2 w^2}\right)^2} \right\}$$

Take the limit as $N^+ \to \infty$:

$$\phi = \frac{al^2 \cos 2\alpha}{2h^2} \left\{ -\frac{1}{2} - \frac{\left(\frac{\pi h}{w}\right)^2}{2\sinh^2\left(\frac{\pi h}{w}\right)} + \sum_{j=1}^{N^-} \frac{\left(1 - \frac{h^2}{j^2 w^2}\right)\frac{h^2}{j^2 w^2}}{\left(1 + \frac{h^2}{j^2 w^2}\right)^2} \right\}$$

References



N.J. Hardiman. Elliptic elastic inclusion in an infinite elastic plate. *QJMAM* **7**, 226–230, 1954.



- H.F. Bueckner. A novel principle for the computation of stress intensity factors. *ZAMM* **46**, 529–545, 1970.
- J.R. Willis & A.B. Movchan. Dynamic weight functions for a moving crack. *JMPS* **43**, 319–341, 1995.



- A. Piccolroaz, G. Mishuris & A.B. Movchan. Symmetric and skew-symmetric weight functions in 2D perturbation models for semi-infinite interfacial cracks. *JMPS* **57**, 1657–1682, 2009.
- A. Piccolroaz, G. Mishuris & A.B. Movchan. Perturbation of Mode III interfacial cracks. *IJF*, 166, 51–41, 2010.



G. Mishuris, A. Movchan, N. Movchan & A. Piccolroaz. Interaction of an interfacial crack with linear small defects under out-of-plane shear loading. *CMS*, in press.



A. Piccolroaz, G. Mishuris, A. Movchan & N. Movchan. Perturbation analysis of Mode III interfacial crack advancing in a dilute heterogeneous material. Submitted.